ANSI/EIA-364-1000A-2016
Approved: February 26, 2016

EIA-364-1000A

EIA STANDARD

TS-1000A

Environmental Test Methodology for Assessing the Performance of Electrical Connectors and Sockets Used in Controlled Environment Applications

EIA-364-1000A

(Revision of EIA-364-1000)

February 2016

Electronic Components Industry Association

This is a preview. Click here to purchase the full publication.

NOTICE

EIA Engineering Standards and Publications are designed to serve the public interest through eliminating misunderstandings between manufacturers and purchasers, facilitating interchangeability and improvement of products, and assisting the purchaser in selecting and obtaining with minimum delay the proper product for his particular need. Existence of such Standards and Publications shall not in any respect preclude any member or nonmember of ECIA from manufacturing or selling products not conforming to such Standards and Publications, nor shall the existence of such Standards and Publications preclude their voluntary use by those other than ECIA members, whether the standard is to be used either domestically or internationally.

Standards and Publications are adopted by ECIA in accordance with the American National Standards Institute (ANSI) patent policy. By such action, ECIA does not assume any liability to any patent owner, nor does it assume any obligation whatever to parties adopting the Standard or Publication.

This EIA standard is considered to have International Standardization implications, but the International Electrotechnical Commission activity has not progressed to the point where a valid comparison between the EIA standard and the IEC document can be made.

This Standard does not purport to address all safety problems associated with its use or all applicable regulatory requirements. It is the responsibility of the user of this Standard to establish appropriate safety and health practices and to determine the applicability of regulatory limitations before its use.

(From Standards Proposal No. SP-5294 formulated under the cognizance of the EIA CE-2.0 Committee on National Connector and Socket Standards).

Published by

©ELECTRONIC COMPONENTS INDUSTRY ASSOCIATION 2016
Standards & Technology Department
2214 Rock Hill Road, Suite 265
Herndon, VA 20170

This is a preview. Click here to purchase the full publication.

PLEASE !
DON'T VIOLATE
THE
LAW!

This document is copyrighted by the ECIA and may not be reproduced without permission.

Organizations may obtain permission to reproduce a limited number of copies through entering into a license agreement. For information, contact:

IHS
15 Inverness Way East
Englewood, CO 80112-5704 or call
USA and Canada (1-877-413-5186), International (303-397-7956)

This is a preview. Click here to purchase the full publication.

CONTENTS

Clause Page

1 Introduction 1

1.1 Scope 1

2 Test specimen 1

2.1 Condition 1
2.2 Sample size 2

3 Test groups 2

4 Details to be specified 12

5 Test documentation 12

Table

1 Test Group 1 (required for all connectors or sockets) 3
2 Test Group 2 (required for all connectors and sockets) 4
3 Test Group 3 (required for all connectors or sockets) 5
4 Test Group 4 (required for connectors or sockets with a precious metal plating on the contacts) 6
4.1 Mixed flowing gas exposure durations 8
5 Test Group 5 (required for connectors or sockets with a tin-based plating on the contacts and optional for connectors or sockets with < 0.38 microns of gold plating on the contacts) 9
6 Test Group 6 (required for connectors or sockets with a surface treatment on the contacts or for connectors or sockets with a wipe length of 0.127 mm or less) 10
7 Test Group 7 (required for connectors or sockets rated for > 50 mating/unmating cycles) 11
8 Test durations (hours) for temperature life 15
9 Test durations (hours) for temperature life (preconditioning) 16
C Test durations (hours) for temperature life complete data C-1
D Test durations (hours) for temperature life (preconditioning) complete data.......... D-1

This is a preview. Click here to purchase the full publication.